Se	earch Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/767,524	PATRIZIO ET AL.		
Examiner	Art Unit		
Eunhee Kim	2123		

SEARCHED			
Class	Subclass	Date	Examiner
703	16,17	10/30/2006	EHC
Above	Updated	4/14/2007	EHC
Above	Updated	10/13/2007	EK
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Conducted Inventor name search	10/30/2006	EHC	
Conducted East BRS text search See attached	10/30/2006	EHC	
Above text search updated	4/14/2007	EHC	
Conducted NPL search of IEEE and ACM	4/14/2007	EHC	
Conducted text search see attached	10/13/2007	EK	
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